



Beam Induced Fluorescence Monitor Developments at GSI heavy Ion Facility

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Non-destructive transverse profile determination:

- No influence to the beam \Rightarrow time dependence evolution detectable
- No risk of material melting by beam power \Rightarrow save operation of the device

Outline of the talk:

- Technical realization for single photon detection generated by residual gas
- Spectroscopic investigations for rare gases and N_2
- Energy scaling of signal strength and background, $1.4\text{MeV/u} < E_{\text{kin}} < 750\text{MeV/u}$
- Conclusion

Expected Signal Strength for BIF-Monitor



Physics:

Energy loss of hadrons in gas dE/dx

⇒ Profile determination from residual gas

- **Ionization:** about 100 eV/ionization
- **Excitation + photon emission:** about 3 keV/photon

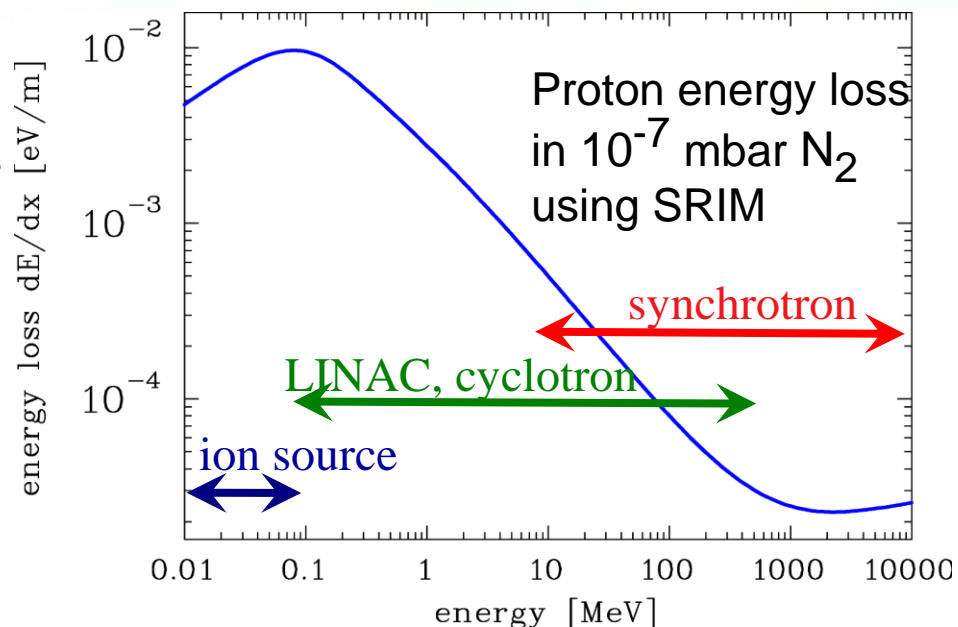
Ionization probability proportional to dE/dx by Bethe-Bloch formula:

$$-\frac{dE}{dx} = \text{const} \cdot \left(\frac{Z_t \cdot \rho_t}{A_t} \right) \cdot Z_p^2 \cdot \left(\frac{1}{\beta^2} \right) \cdot \left[\ln \left(\text{const} \cdot \frac{\gamma^2 \beta^2}{W_{\max}} \right) - \beta^2 \right]$$

Target electron density:
 Proportional to vacuum pressure
 ⇒ Adaptation of signal strength

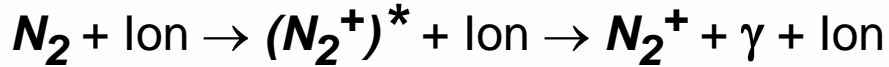
$\propto 1/E_{kin}$ (for $E_{kin} > 1\text{GeV}$ nearly constant)

Strong dependence on projectile charge for ions A^{Z_p}



Beam Induced Fluorescence Monitor: Principle

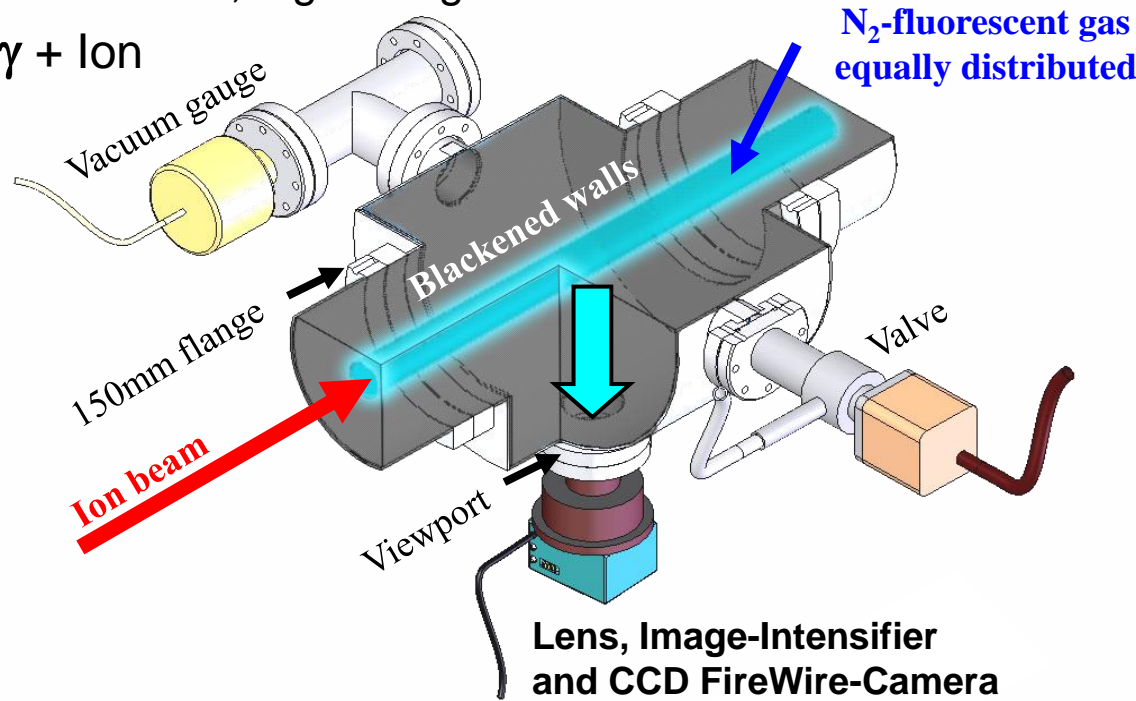
Detecting *photons* from residual gas molecules, e.g. Nitrogen



$390 \text{ nm} < \lambda < 470 \text{ nm}$

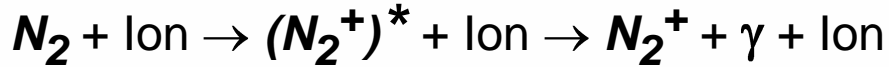
emitted into solid angle Ω to camera

single photon detection scheme



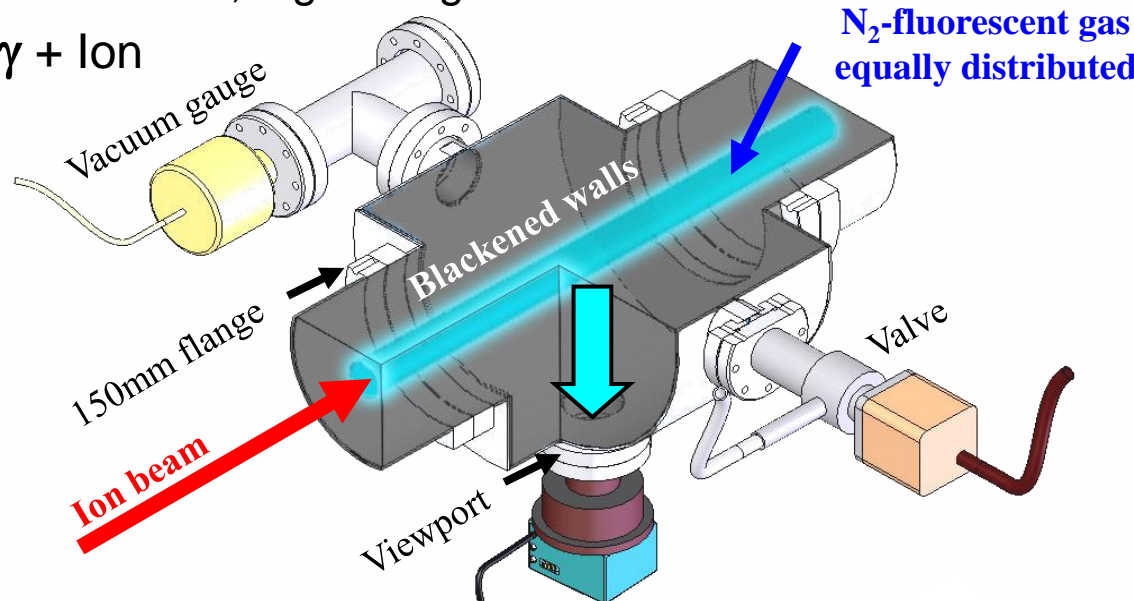
Beam Induced Fluorescence Monitor: Principle

Detecting **photons** from residual gas molecules, e.g. Nitrogen



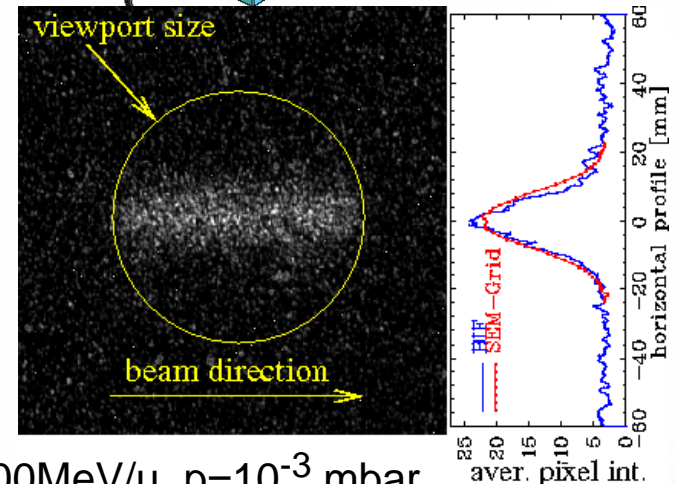
$390 \text{ nm} < \lambda < 470 \text{ nm}$

emitted into solid angle Ω to camera
single photon detection scheme



Features:

- Single pulse observation possible down to $\approx 1 \mu\text{s}$ time resolution
- High resolution (here 0.2 mm/pixel) can be easily matched to application
- Commercial Image Intensifier
- Less installations inside vacuum as for IPM
⇒ compact installation e.g. 20 cm for both panes



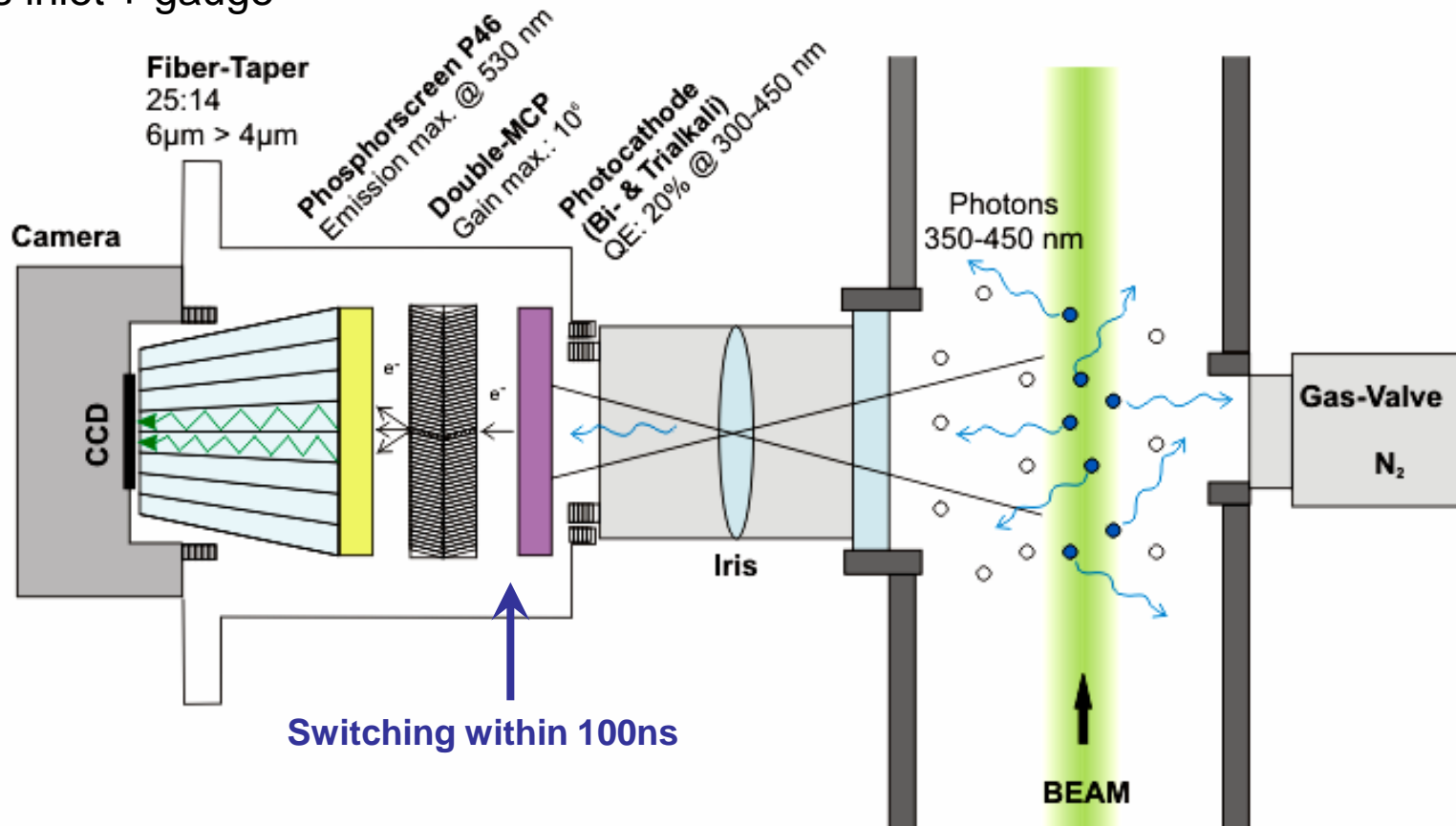
Beam: $4 \times 10^{10} \text{ Xe}^{48+}$ at 200MeV/u, $p=10^{-3}$ mbar

BIF-Monitor: Technical Realization



Example BIF station at GSI-LINAC:

- 2 x image intensified CCD cameras: photon \rightarrow e^- \rightarrow amplification of e^- \rightarrow photons \rightarrow CCD
- Optics with reproduction scale 0.2 mm/pixel
- Gas inlet + gauge

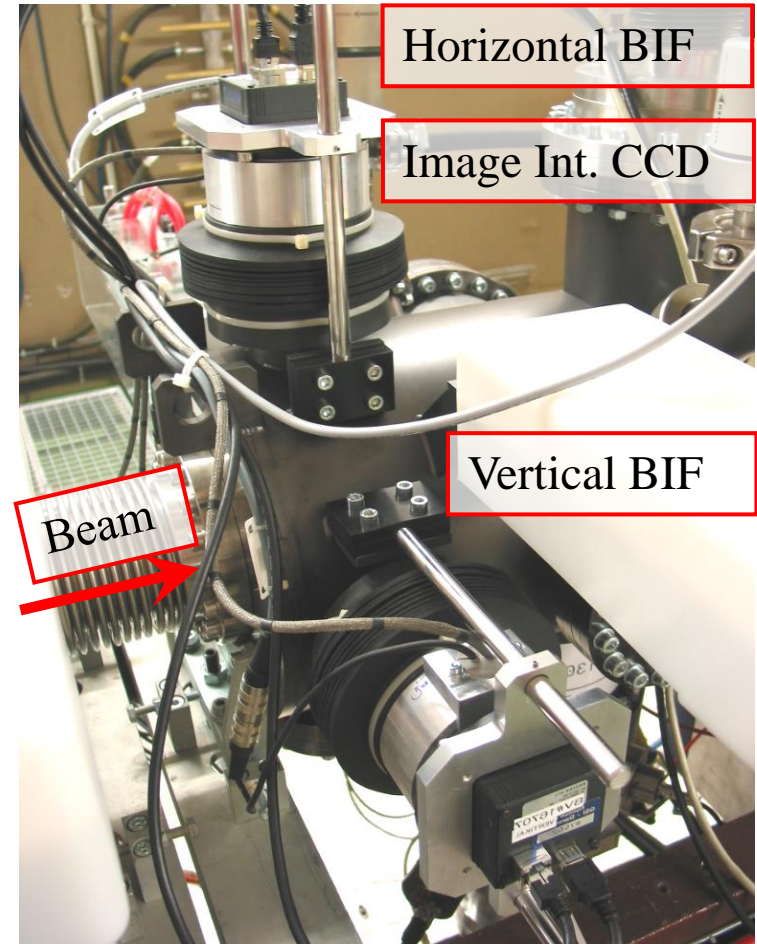
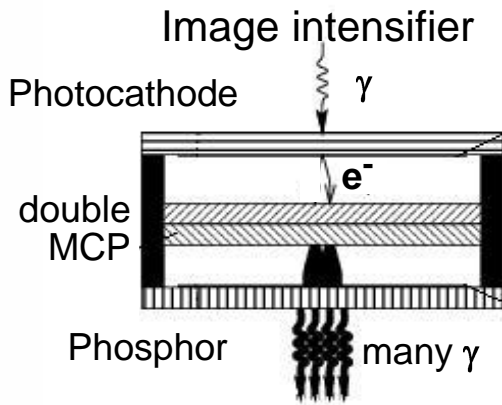


BIF-Monitor: Technical Realization

Example BIF station at GSI-LINAC:

- 2 x image intensified CCD cameras
- Optics with reproduction scale 0.2 mm/pixel
- Gas inlet + gauge
- Pneumatic feed-through for calibration
- Insertion length 25 cm for both directions only

Realization at other labs (e.g. BNL, CERN, FZJ):
Segmented photomultiplier, CID or emCCD



Examples from Ion LINAC at GSI



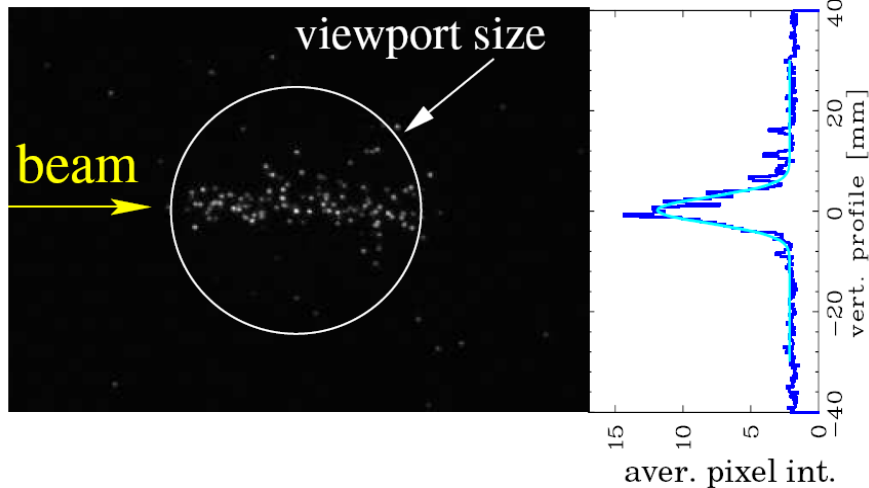
Single pulse observation

4.7 MeV/u Ar¹⁰⁺ beam

I=2.5 mA equals to 10¹¹ particles

One single macro pulse of 200 μs

Vacuum pressure: p=10⁻⁵ mbar (N₂)



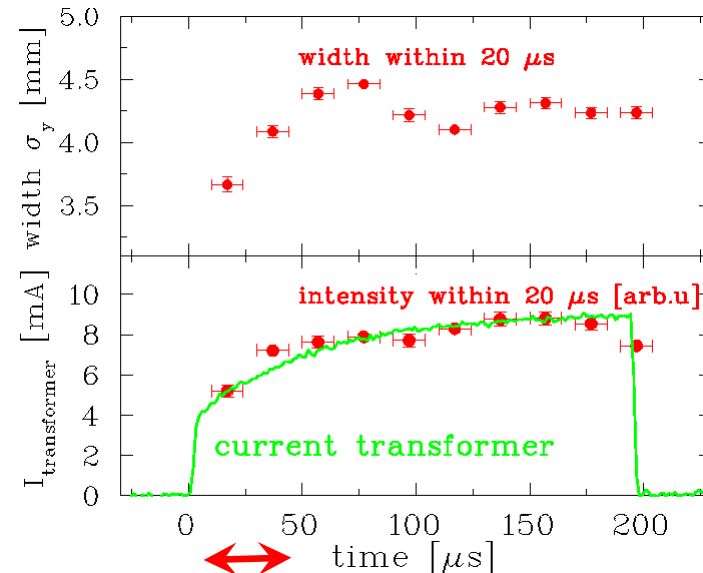
Installed at several location along UNILAC

Time resolved observation

Variation **during** the macro pulse detectable:

Switching of image intensifier (within 100 ns)

→ 20 μs exposure window during macro-pulse



8 mA Ar¹⁰⁺
at 11 MeV/u

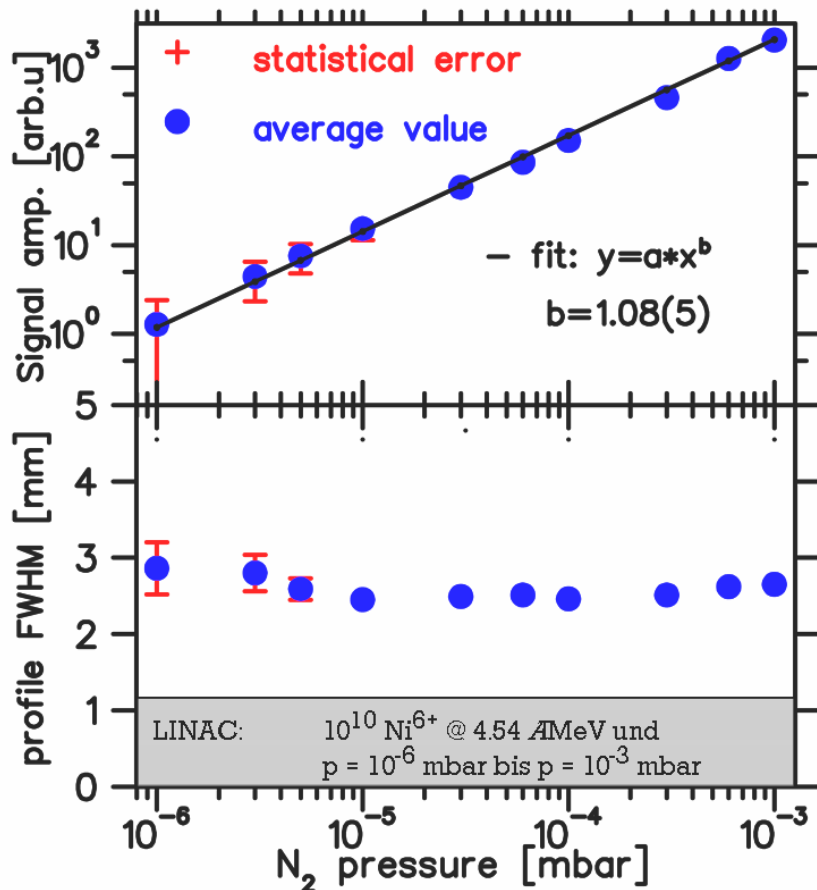
Further application: Background suppression by matching the exposure to beam delivery



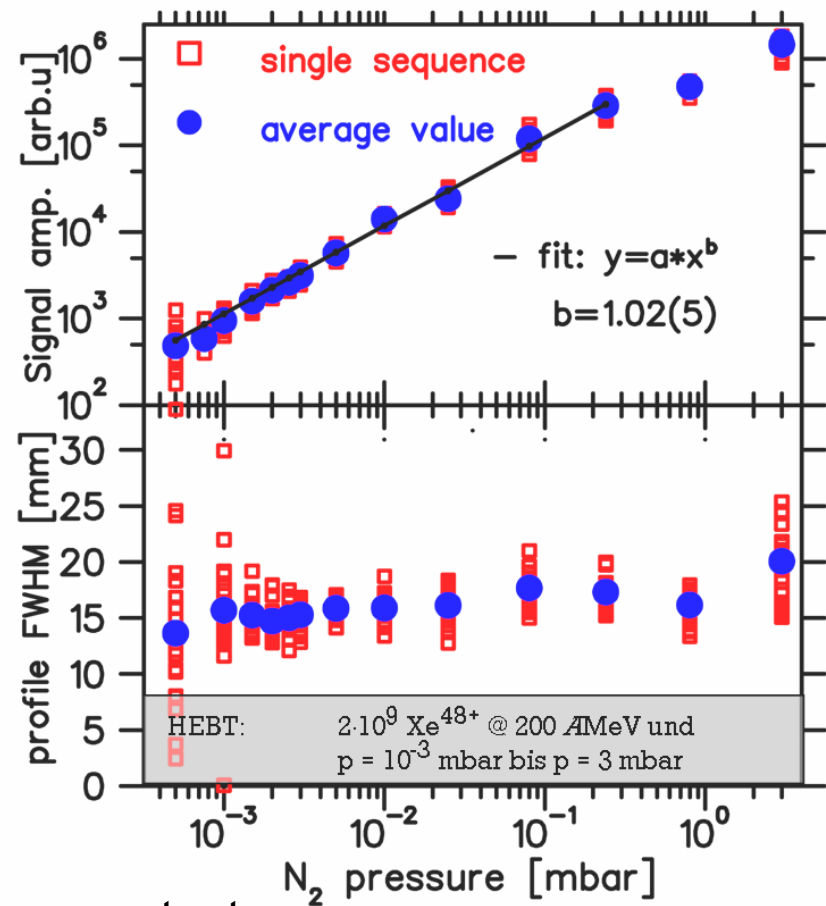
Variation of N_2 Pressure over 6 Orders of Magnitude



UNILAC: Ni^{6+} at 4,5 MeV/u



Behind SIS-18: Xe^{48+} at 200 MeV/u



Results: signal amplitude $\propto p$ and $\sigma = \text{constant}$
 \Rightarrow gas pressure up to 1 mbar is a free parameter

Energy Scaling behind SIS18 at GSI

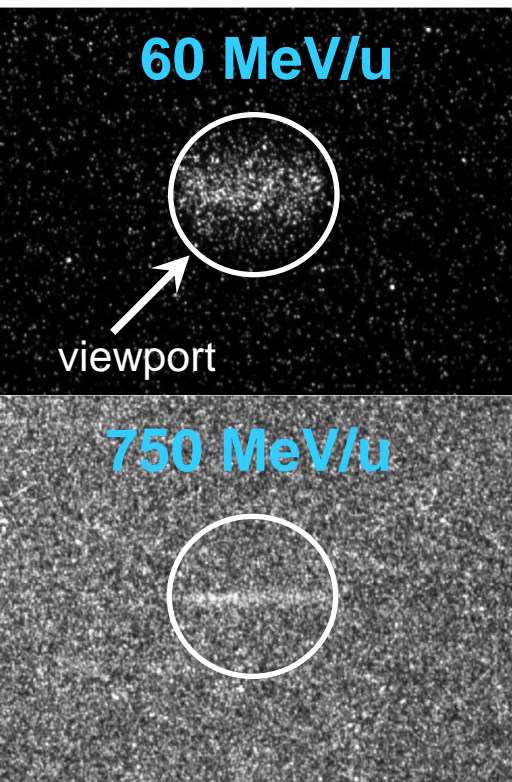
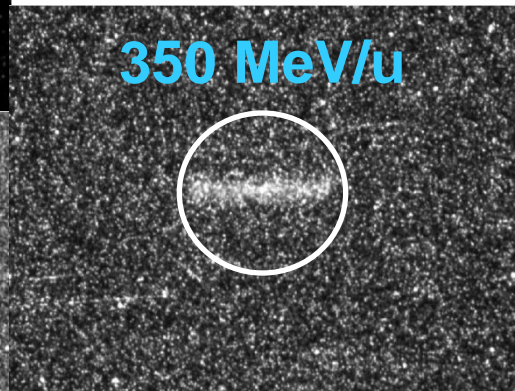
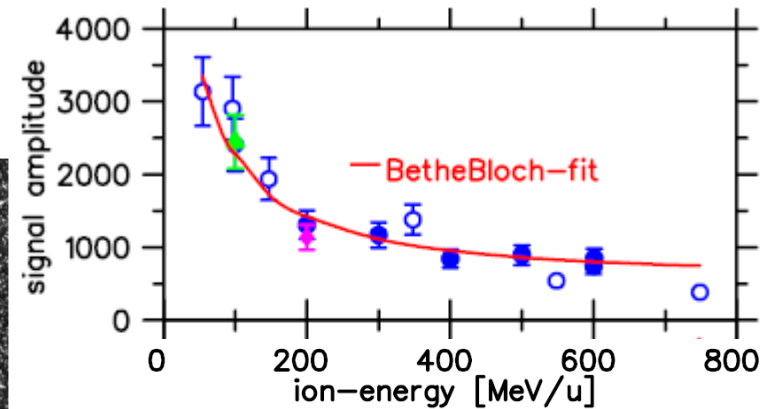


Image from $1 \cdot 10^9$ U
 $p = 2 \cdot 10^{-3}$ mbar,
mounted ≈ 2 m
before beam-dump:



E_{kin} dependence for signal
& background close to beam-dump:



- Signal proportional to energy loss
- Suited for FAIR-HEBT with $\geq 10^{10}$ ions/pulse

Energy Scaling behind SIS18 at GSI

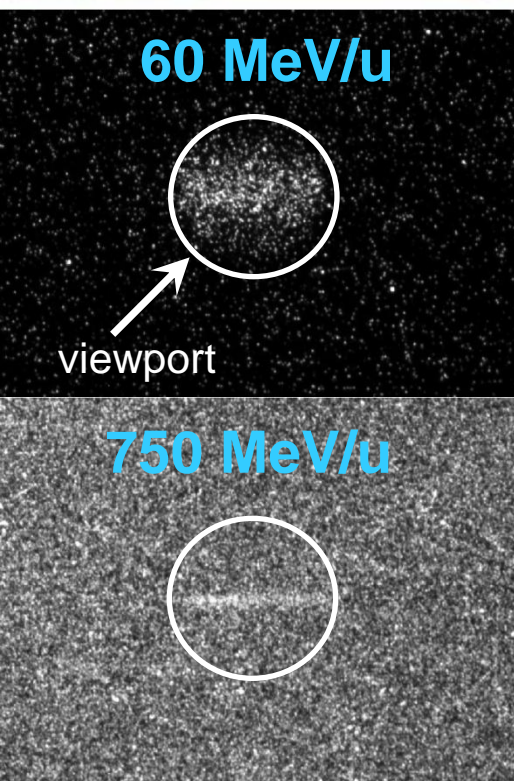
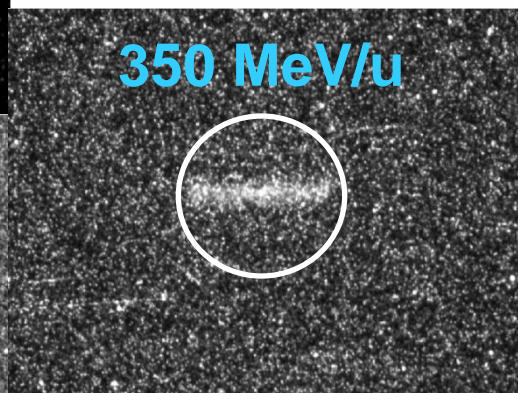
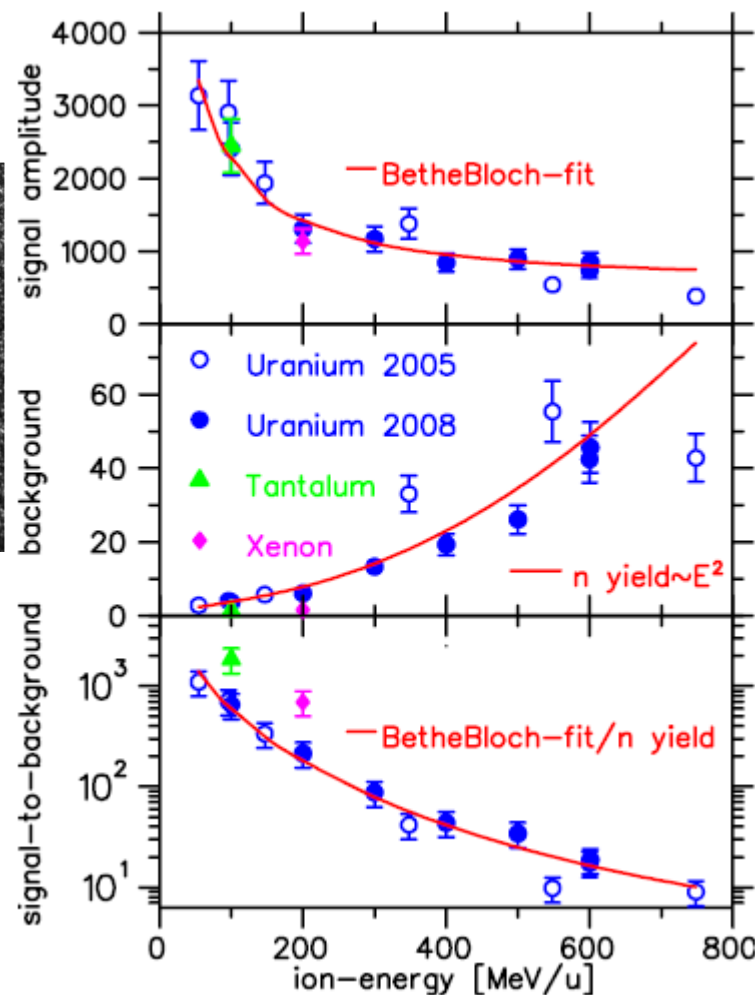


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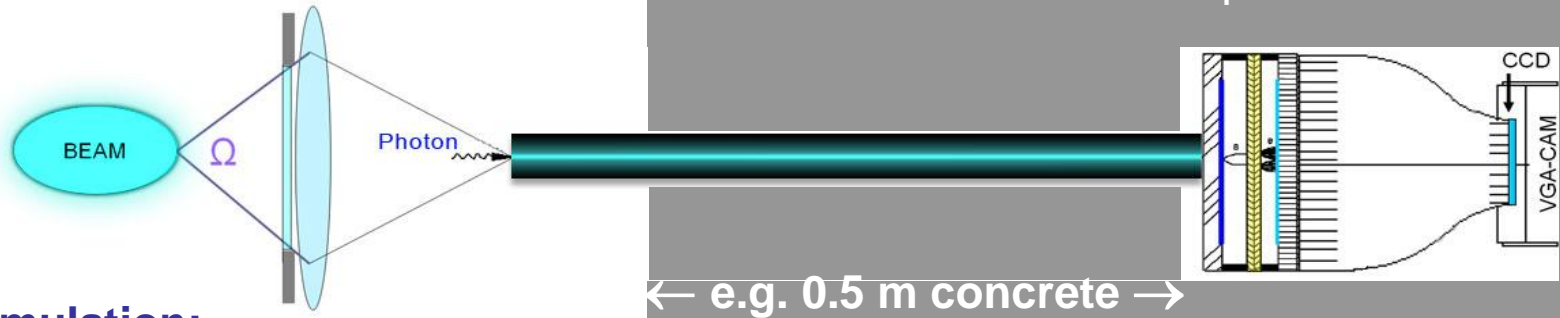


E_{kin} dependence for signal
 & background close to beam-dump:



- Signal proportional to energy loss
- Suited for FAIR-HEBT with $\geq 10^{10}$ ions/pulse
- Background prop. $E_{kin}^2 \Rightarrow$ shielding required
- Background suppression by 1 m fiber bundle

Shielding Concept for Background Reduction



Effective neutron shielding:
moderation and absorption

FLUKA simulation:

Shielding of 1x1x1 m³ concrete block:

900 MeV/u BIF monitor 2m to beam dump

⇒ γ & n reduction 95 %

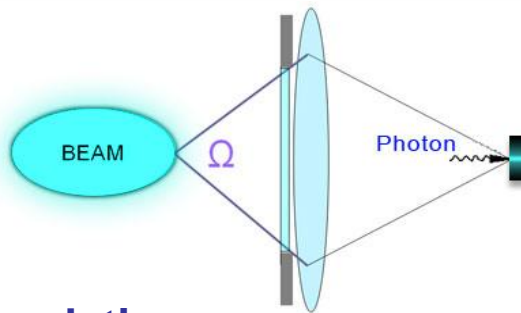
Fiber-optic bundle with ≈ 1 million fibers:

- Commercial device for reduction of background and CCD destruction
- Image Intensifier and CCD in shielded area
- larger distance but same solid angl

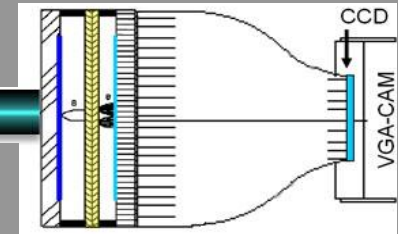
Experimental results:

- No significant image distortion
 - Low scintillation by n & γ inside bundle
- un-shielded: ≈ 30 % increase of background

Shielding Concept for Background Reduction



Effective neutron shielding:
moderation and absorption



← e.g. 0.5 m concrete →

FLUKA simulation:

Shielding of 1x1x1 m³ concrete block:

900 MeV/u BIF monitor 2m to beam dump

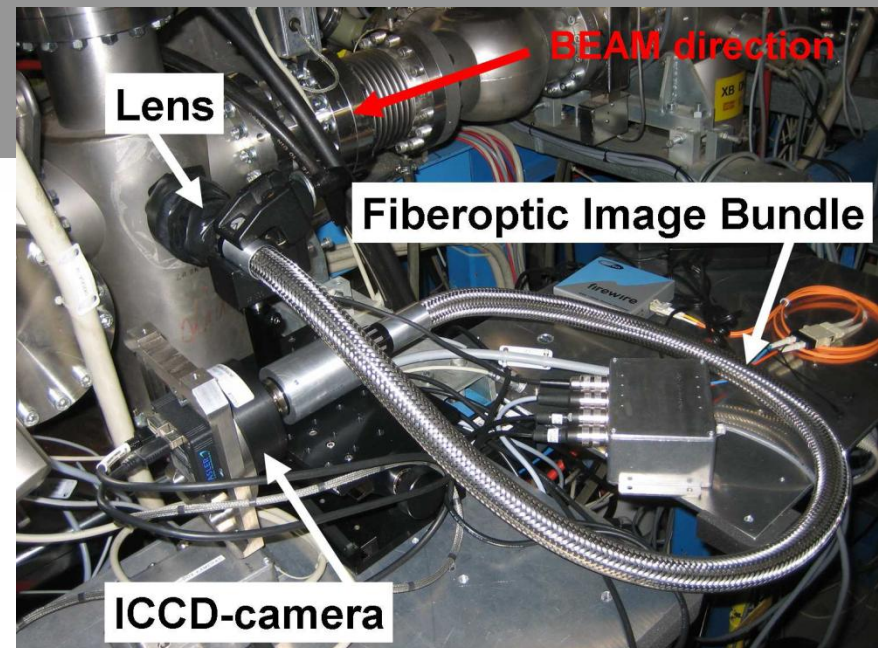
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- No significant image distortion
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Spectroscopy – Color and Fluorescence Yield



Beam: S^{6+} at 5.16 MeV/u, $p_{N_2} = 10^{-3}$ mbar

Results of detailed investigations:

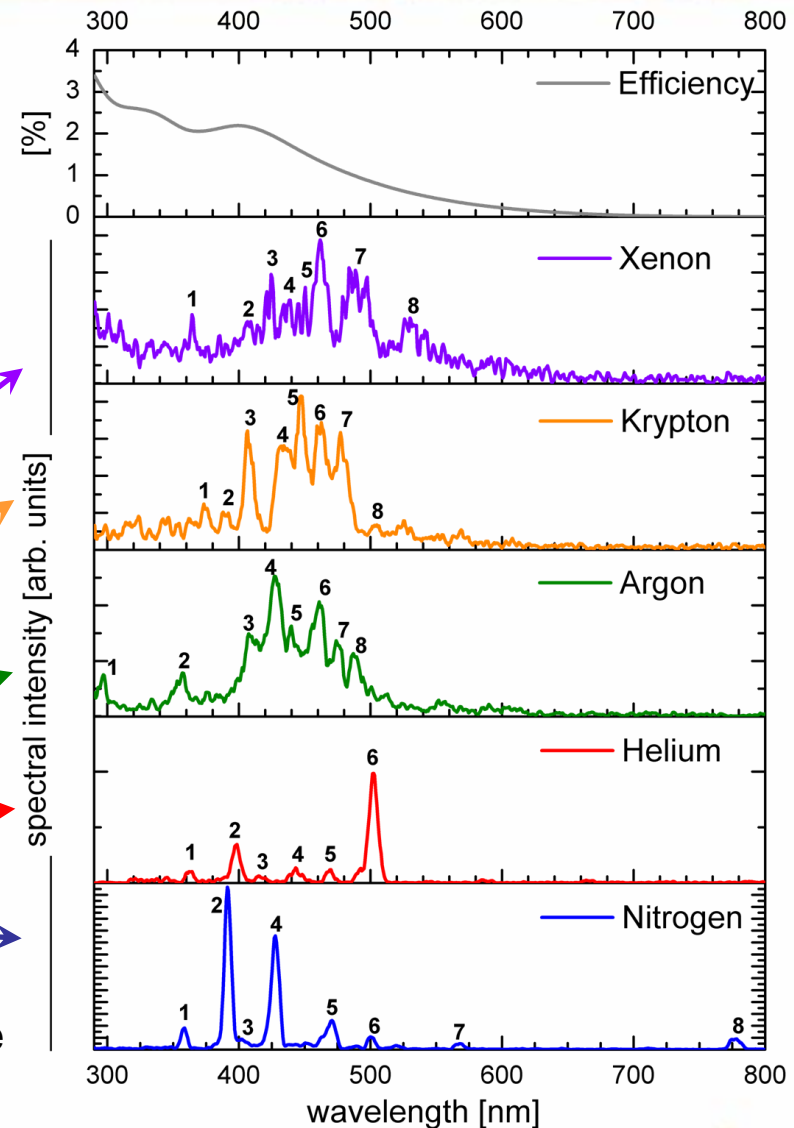
- Rare gases and N_2 : green to near-UV
- Compact wavelength interval for N_2
- Fluorescence yield: $N_2 \approx 4x$ higher as rare gases

⇒ N_2 and Xe are well suited !

Relative fluorescence yield Y (all wavelength):

gas	Y for p	Y for p/n_e
Xe	86 %	22 %
Kr	63 %	25 %
Ar	38 %	30 %
He	4 %	26 %
N_2	100 %	100 %

n_e : gas electron density \propto energy loss \Leftrightarrow beam influence



Spectroscopy – Profile Reading

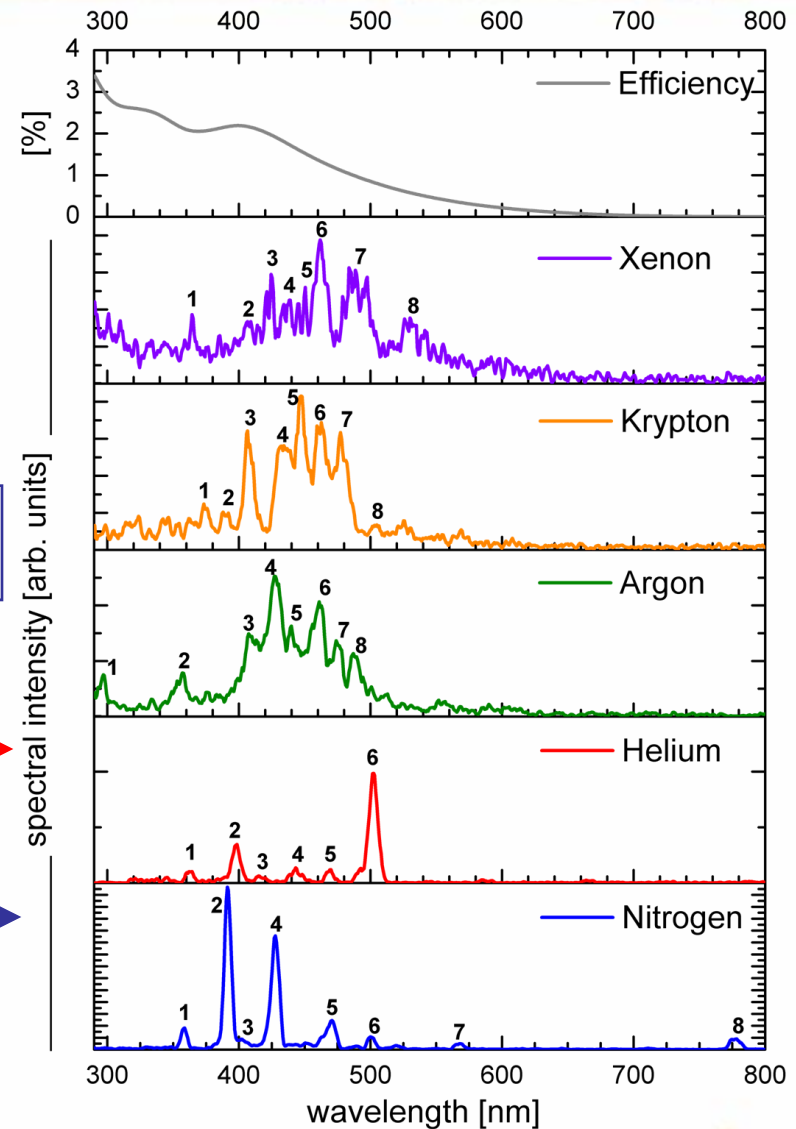
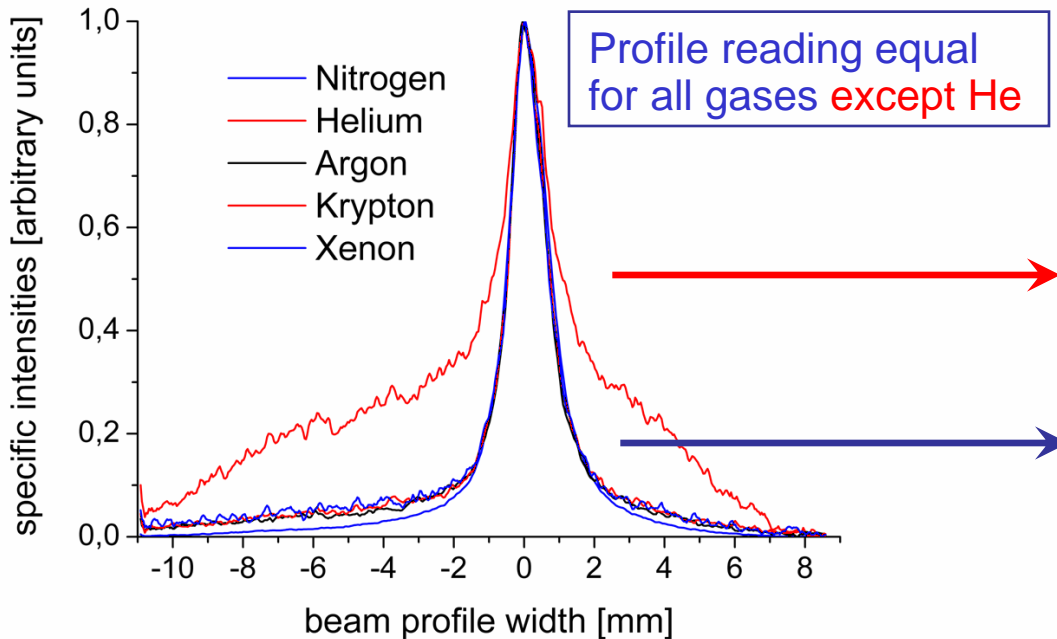


Beam: S^{6+} at 5.16 MeV/u, $p_{N_2} = 10^{-3}$ mbar

Results of detailed investigations:

- Rare gases and N_2 : green to near-UV
 - Compact wavelength interval for N_2
 - Fluorescence yield: $N_2 \approx 4x$ higher as rare gases
 - Same profile image for **all** gas, **except He**
- ⇒ N_2 and Xe are well suited !

Normalized profile reading for all λ :



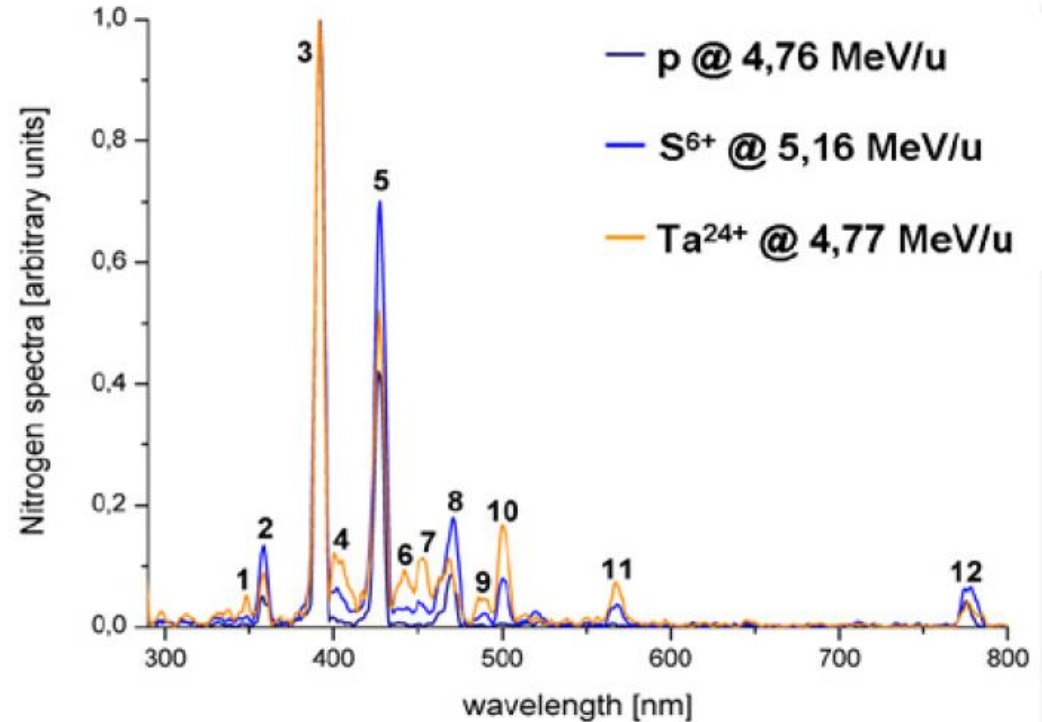
Spectroscopy – Excitation by different Ions



For N_2 working gas the spectra for different ion impact is measured:

Results:

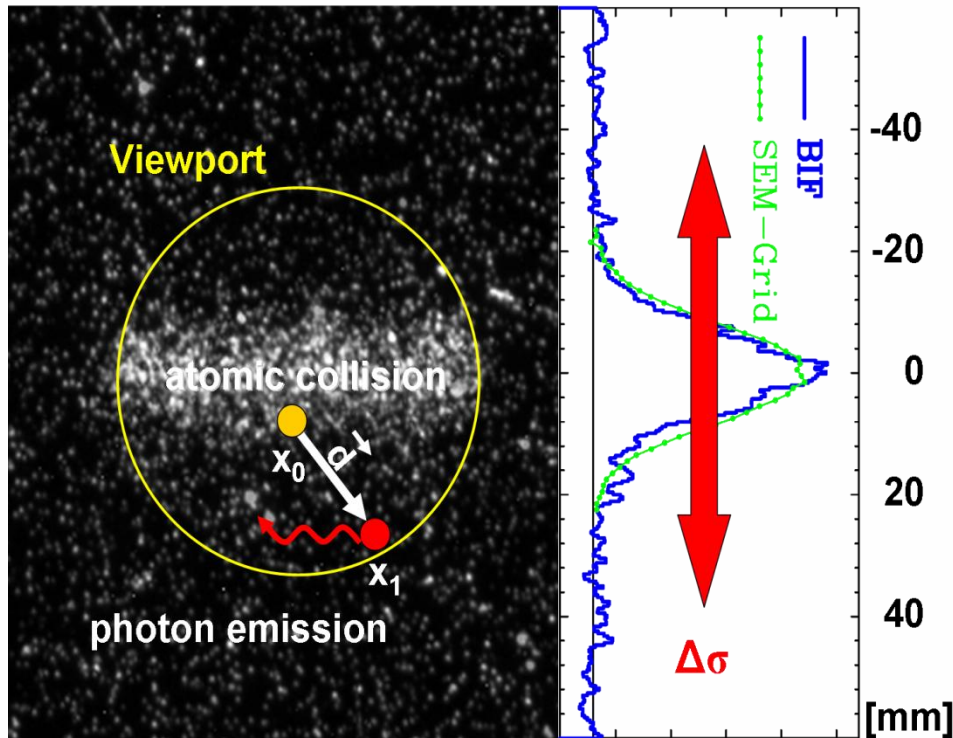
- Comparable spectra for all ions
 - Small modification due to N_2^+ dissociation by heavy ion impact
 - Results fits to measurements for proton up to 100 GeV at CERN
- ⇒ Stable operation possible for N_2



Care: Different physics for $E_{kin} < 100$ keV/u $\Leftrightarrow v_{coll} < v_{Bohr}$

→ Different spectra measured

Systematic Errors → Movement in Beam's E-Field



BIF-profiles represent x_1 the location of photon-emission

➤ Gas-dynamics and lifetime of excited fluorescence states influence profile errors (not important present GSI beam parameter but for FAIR)

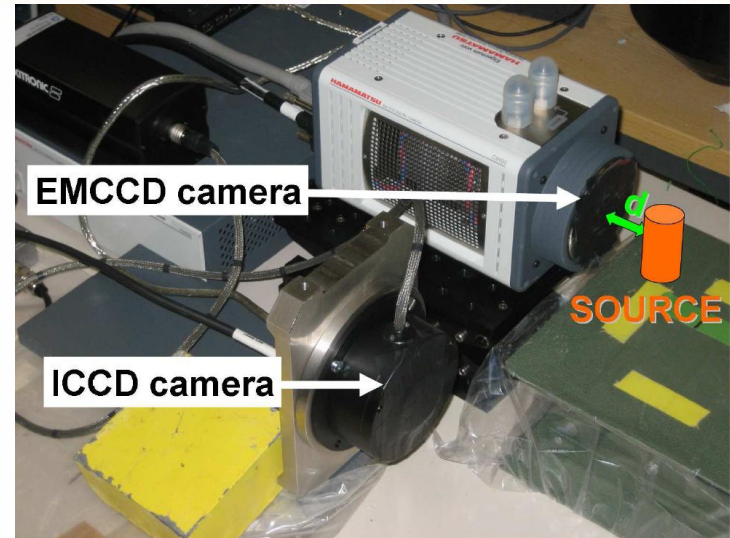
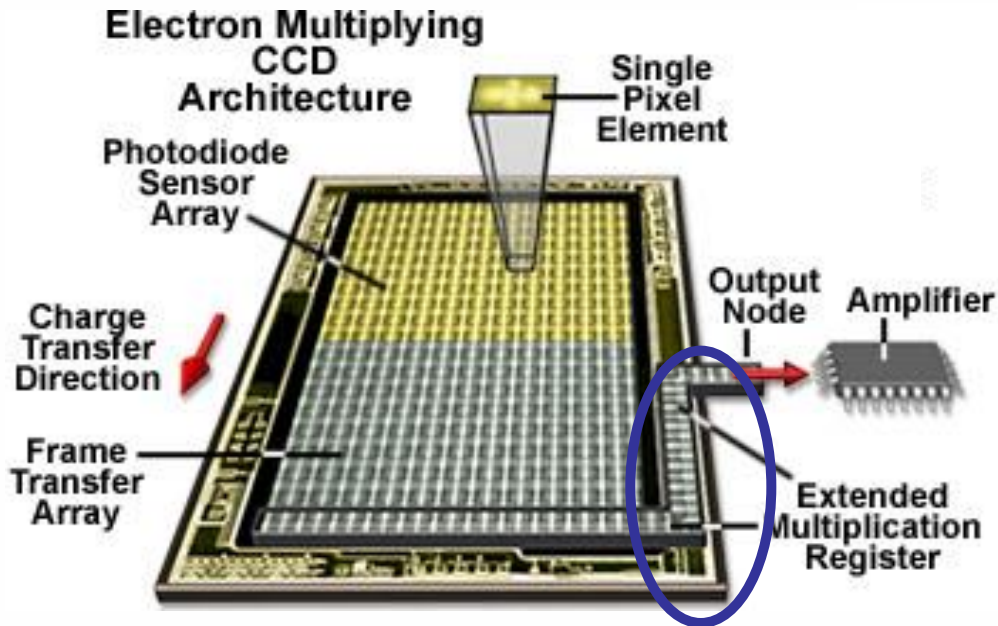
➤ Gas-dynamics defined by:

- Lifetime e.g. **N₂**: 58 ns **Xe**: 6 ns
- Mass and ionic charge
- Dissociation-kinetics
- **For ions E-field of the beam**

Xe as an alternative gases with 5-fold higher mass and 10-fold shorter optical lifetimes as **N₂**

Alternative Single Photon Camera: emCCD

Principle of electron multiplication CCD:



Multiplication by avalanche diodes:

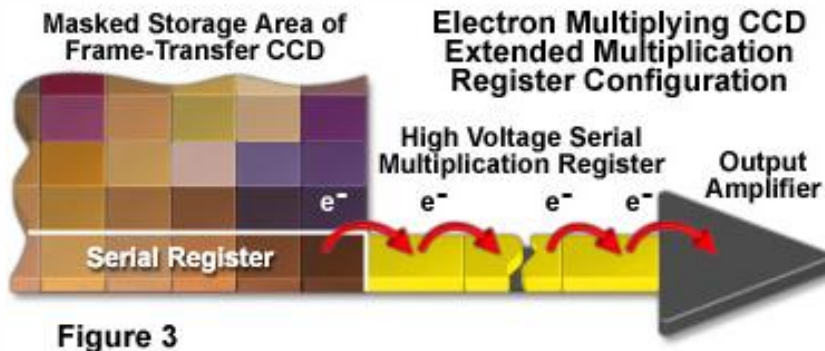


Figure 3

Parameter of Hamamatsu C9100-13

Pixel: 512x512, size $16 \times 16 \mu\text{m}^2$

Maximum amplification: x1200

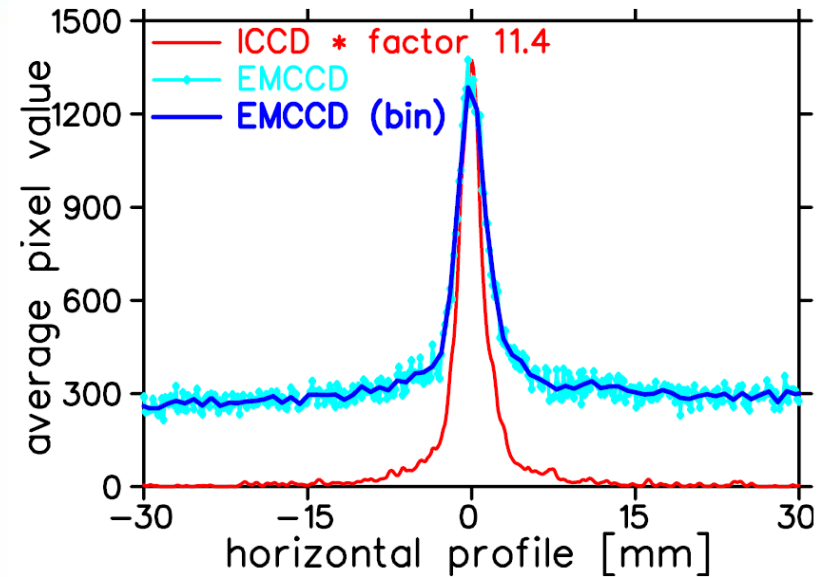
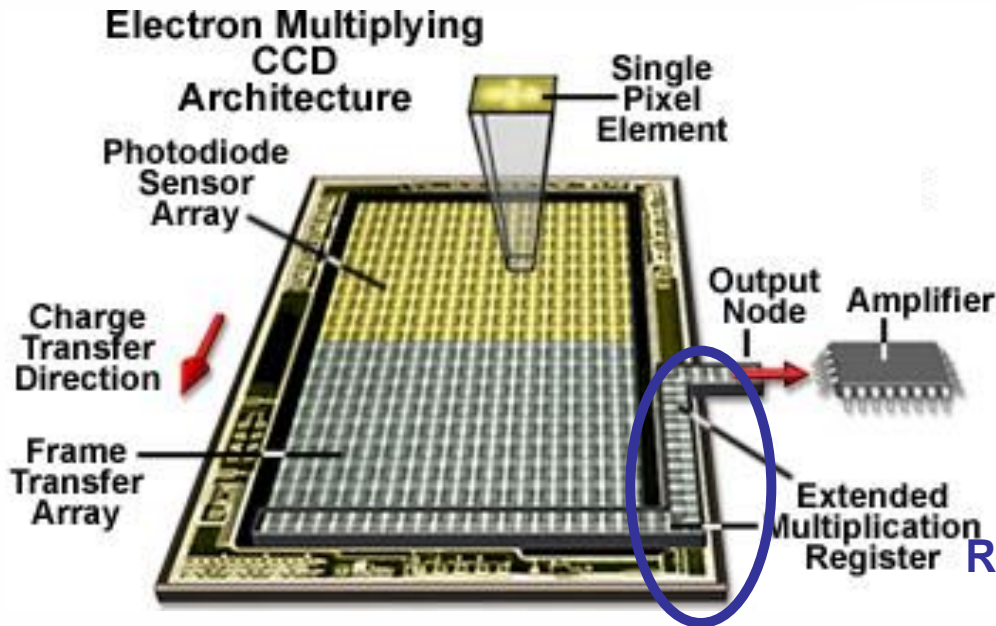
Temperature of emCCD sensor: $-80 \text{ }^\circ\text{C}$

Readout noise: about $1 e^-$ per pixel

Alternative Single Photon Camera: emCCD



Principle of electron multiplication CCD:



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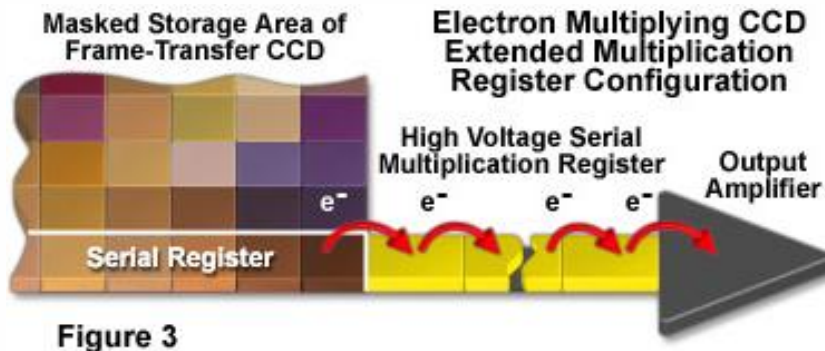


Figure 3

Results: Suited for single photon detection
 x5 higher spatial resolution as ICCD
 more noise due to electrical amplification

⇒ Acts as an alternative

Parameter of Hamamatsu C9100-13

Pixel: 512x512, size 16x16 μm^2

Maximum amplification: x1200

Temperature of emCCD sensor: -80 $^{\circ}\text{C}$

Readout noise: about 1 e^- per pixel



Summary Beam Induced Fluorescence Monitor



- Non-destructive profile method demonstrated (single photon detection possible)
- Independence of profile reading for pressures up to 10^{-1} mbar for **N₂, Xe, Kr, Ar**
- Operational usage at UNILAC started, pressure typ. $p < 10^{-5}$ mbar
- Shielding concept partly demonstrated
- Modern emCCD might be an alternative
- **N₂** is well suited: blue wavelength, good vacuum properties, high light yield
- **Xe** is an alternative due to 10-fold shorter lifetime: less influence in beam's E-field
- **He** is **excluded** as working gas due to wrong profile reproduction
- **Future:** Working gas pressure up 1 bar (i.e. mean free path \ll beam diameter)
- **Future:** Investigation of shielding and radiation hardness of components
- **Future:** Investigation as target diagnostics for RIB, neutrons or antiprotons

Acknowledgement: F. Bieniosek(LBNL), A. Ulrich (TU-München)

Thank you for your attention!



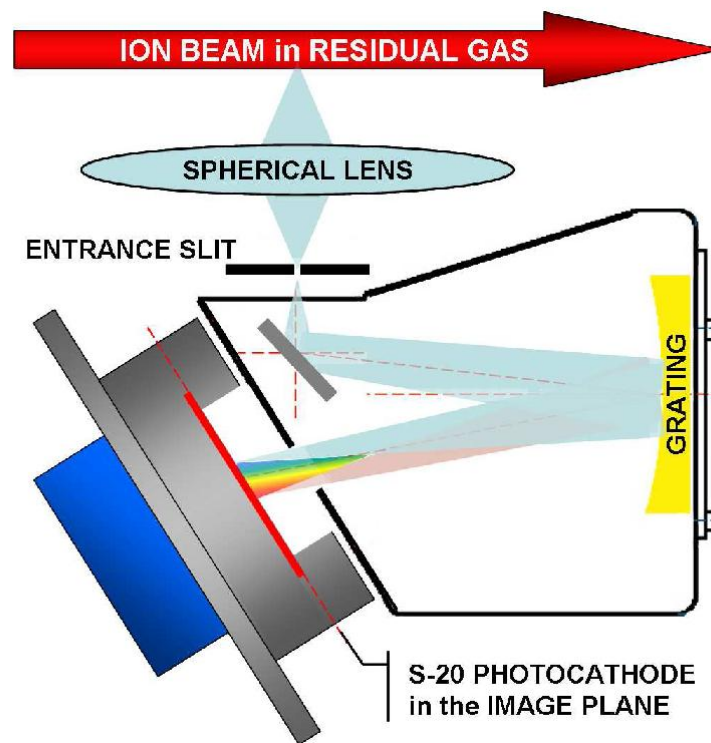
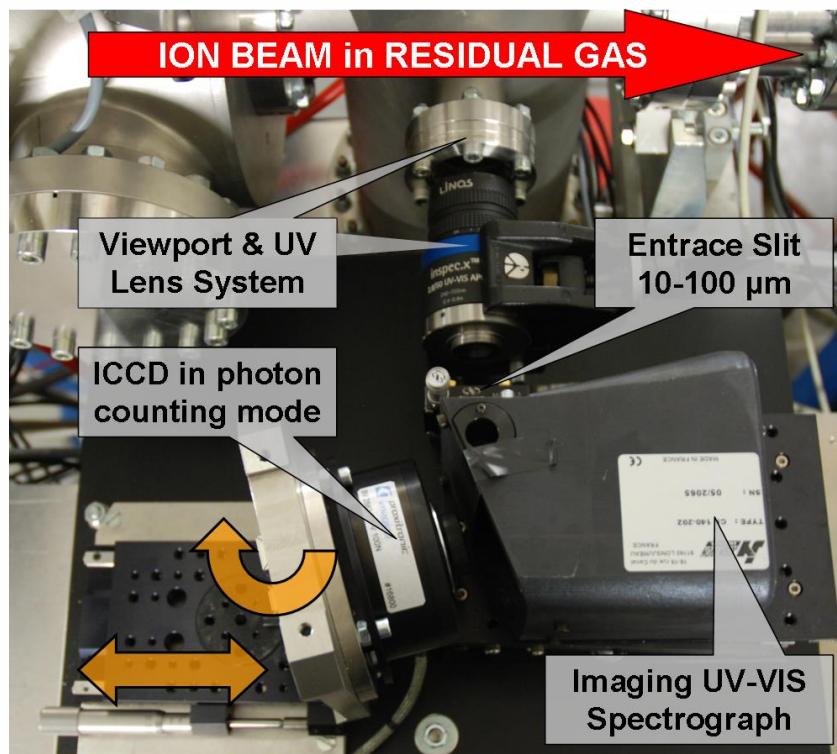
Spare transparencies

Spectroscopic Investigations for BIF



Investigations of light yield and wavelength spectrum for N_2 and rare gases.

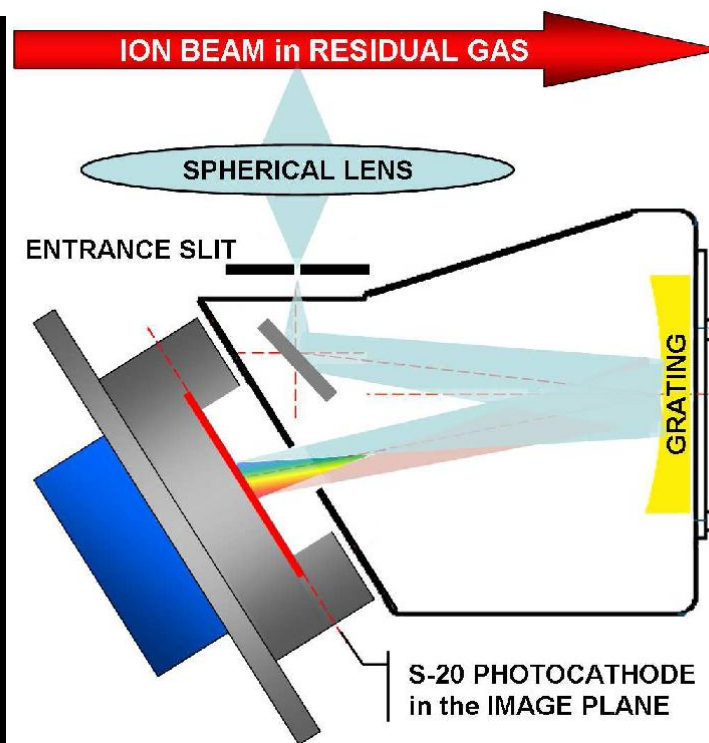
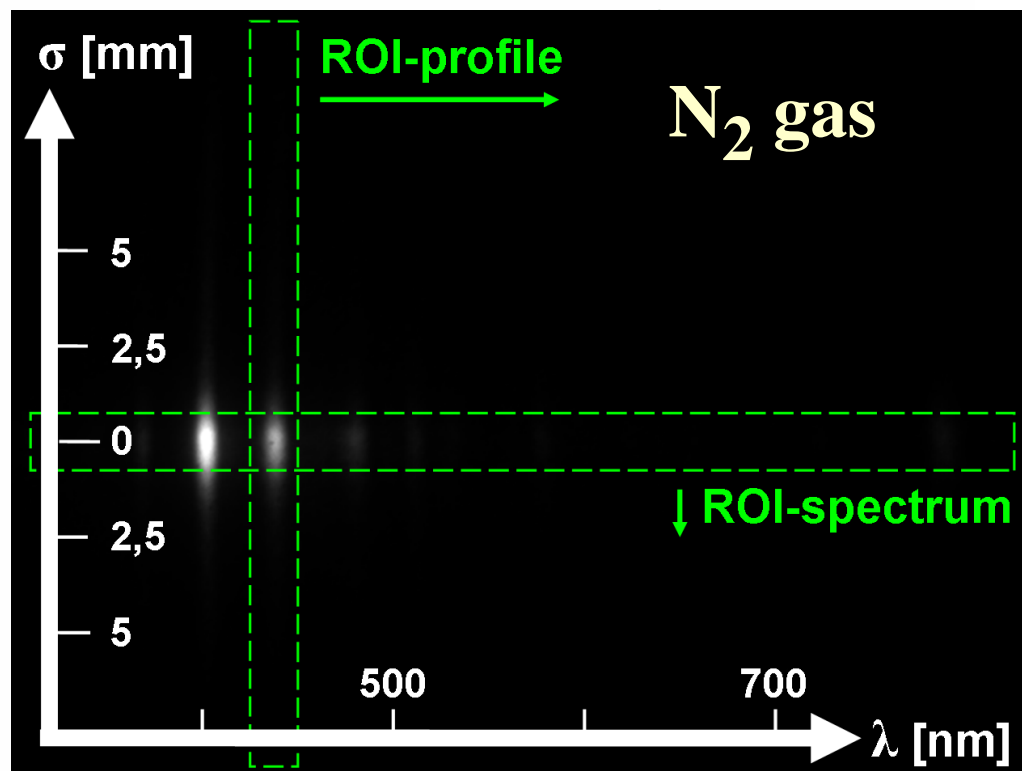
Imaging Spectrograph installed behind UNILAC: Wavelength selective beam profile





Investigations of light yield and wavelength spectrum for N₂ and rare gases.

Imaging Spectrograph installed behind UNILAC: Wavelength selective beam profile

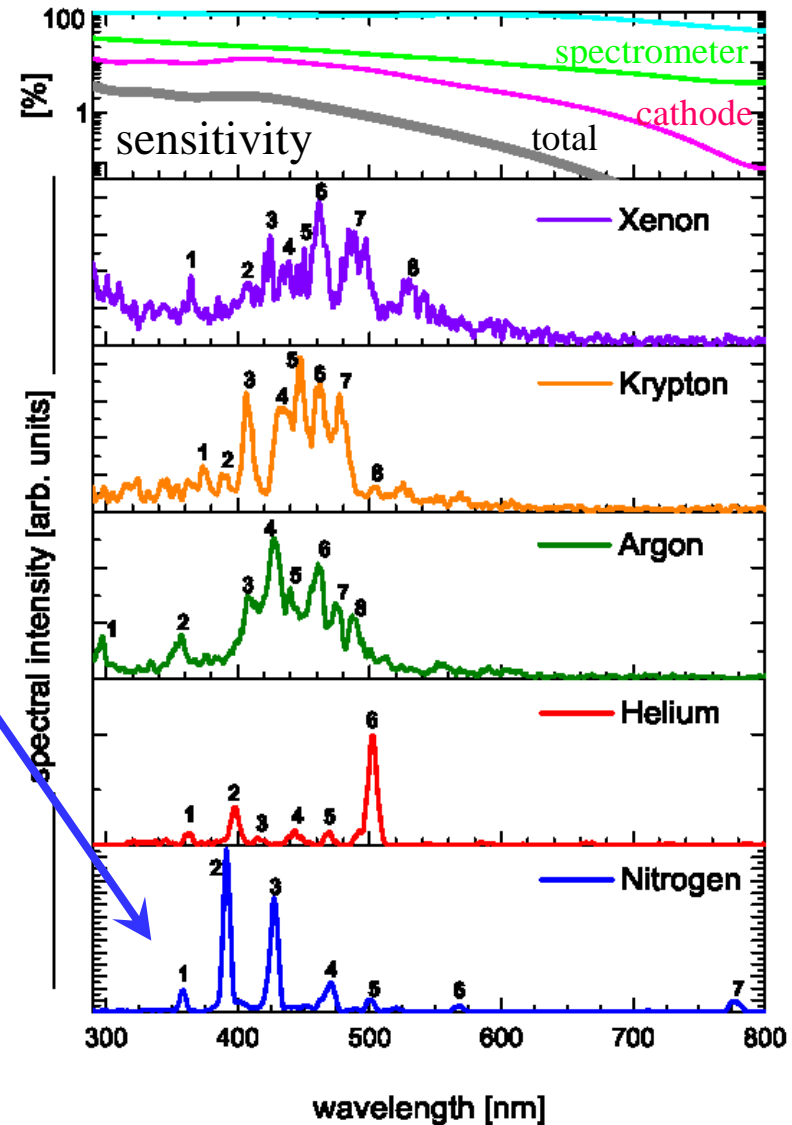
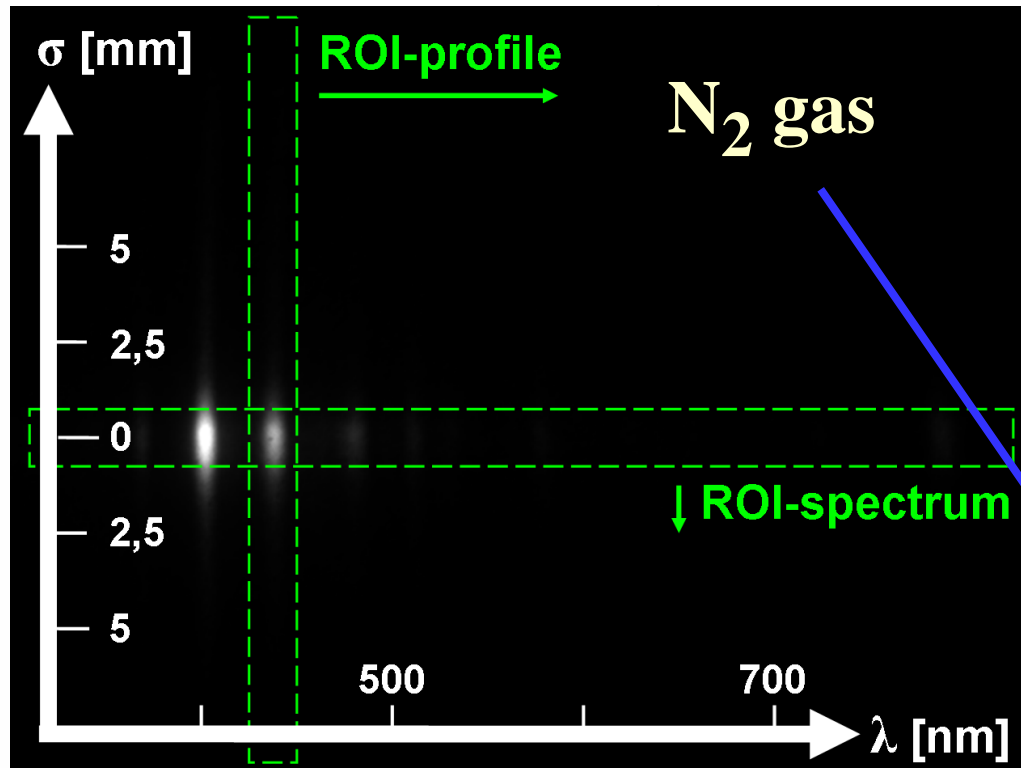


Beam parameter: S⁶⁺ at 5.16 MeV/u with $3 \cdot 10^{11}$ pps,
2000 macro-pulses, $p_{N_2} = 10^{-3}$ mbar

Spectroscopic Investigations for BIF of N₂: Wavelength



⇒ Expected transitions in near-UV to blue
(as for slower and faster collisions with protons)

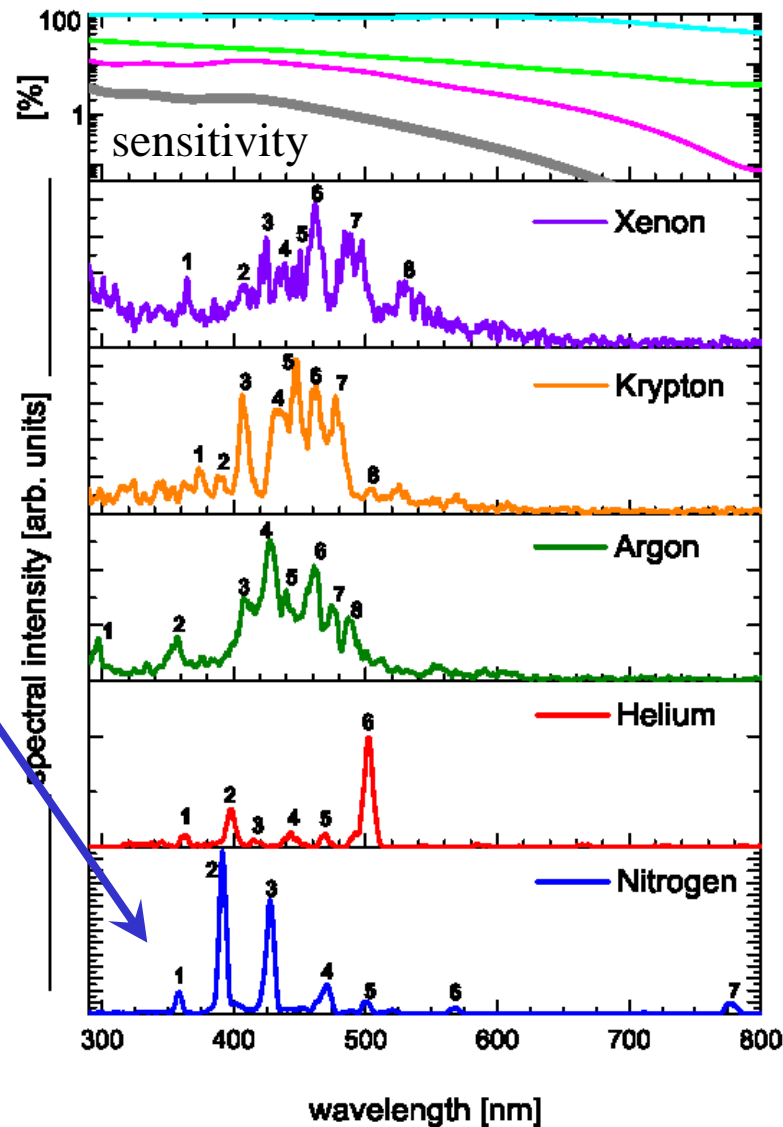
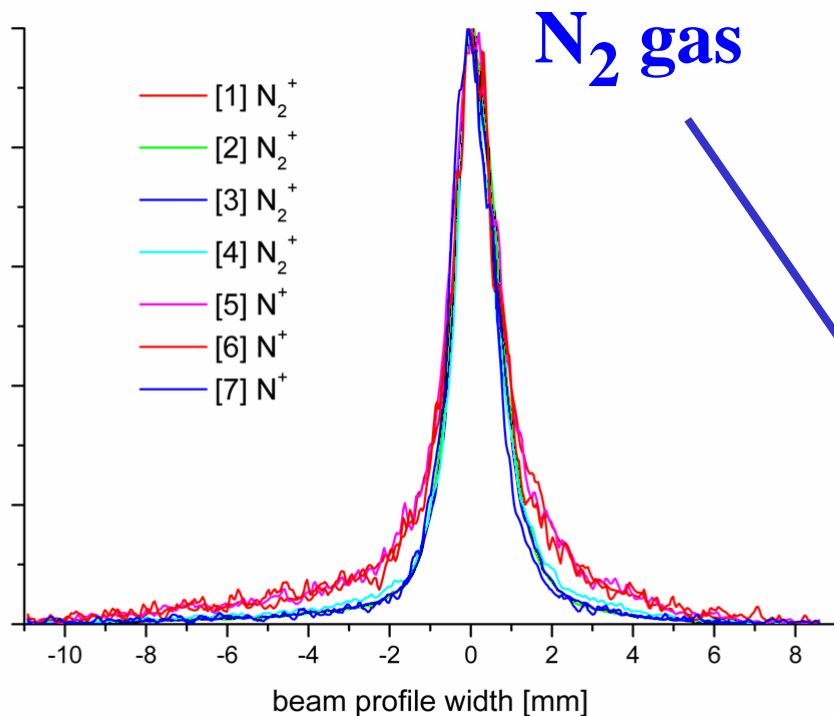


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Spectroscopic Investigations for BIF of N₂: Profile Reading



- ⇒ Expected transitions in near-UV to blue
(as for slower and faster collisions with protons)
- ⇒ Same profile reading for all lines



Beam parameter: S⁶⁺ at 5.16 MeV/u with $3 \cdot 10^{11}$ pps,
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Spectroscopic Investigations for BIF of N₂: Light Yield

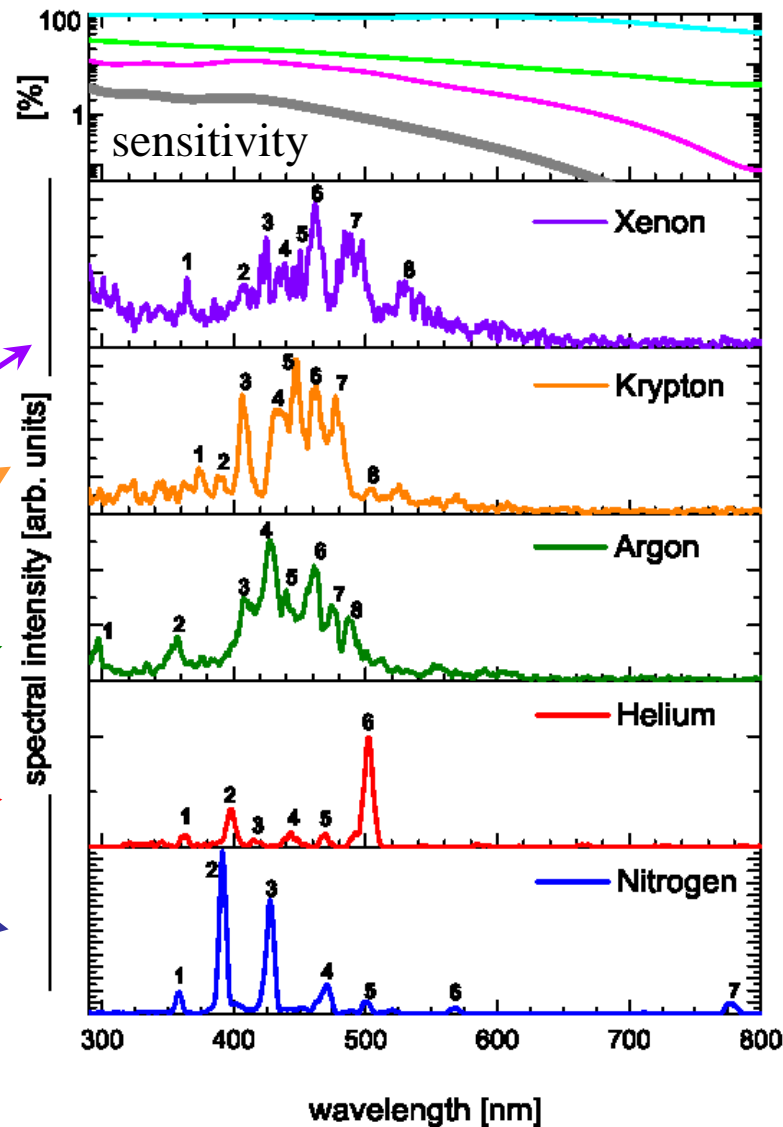
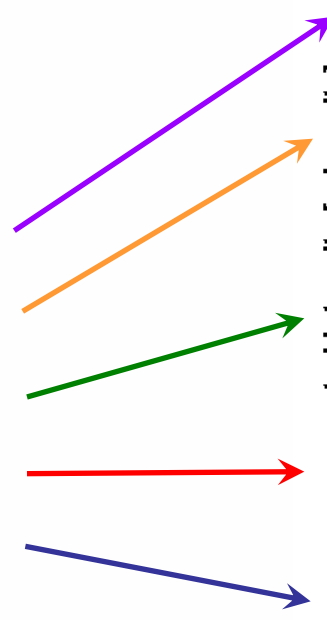


- ⇒ Expected transitions in near-UV to blue (as for slower and faster collisions with protons)
- ⇒ Same profile reading for all lines
- ⇒ Light yield of N₂ is factor 4 higher as rare gases
- ⇒ *N₂ is well suited!*

Normalized light yield for all λ :

gas	I:p N ₂	I: P _{real}	I: p _{real} /Z
Xe	41 %	86 %	22 %
Kr	45 %	63 %	25 %
Ar	50 %	38 %	30 %
He	21 %	4 %	26 %
N ₂	100%	100 %	100 %

$p_{\text{real}}/Z \propto n_e \propto dE/dx$ stopping power



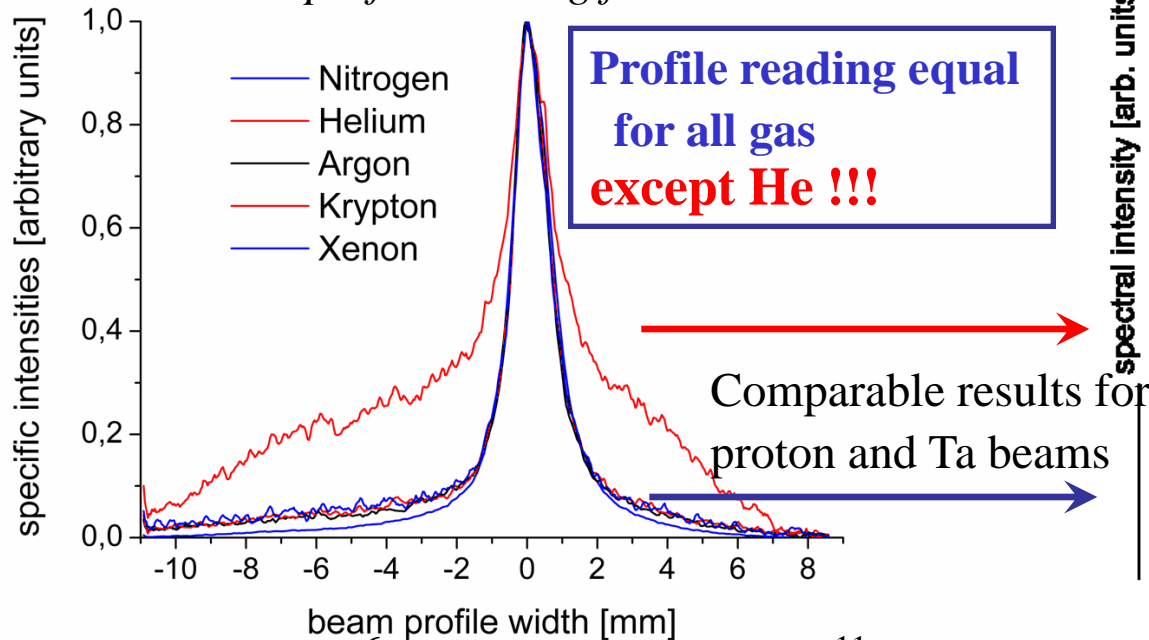
Beam parameter: S⁶⁺ at 5.16 MeV/u with 3·10¹¹ pps,
2000 macro-pulses, p_{N₂}=10⁻³ mbar

Spectroscopic Investigations for BIF of N₂ and He

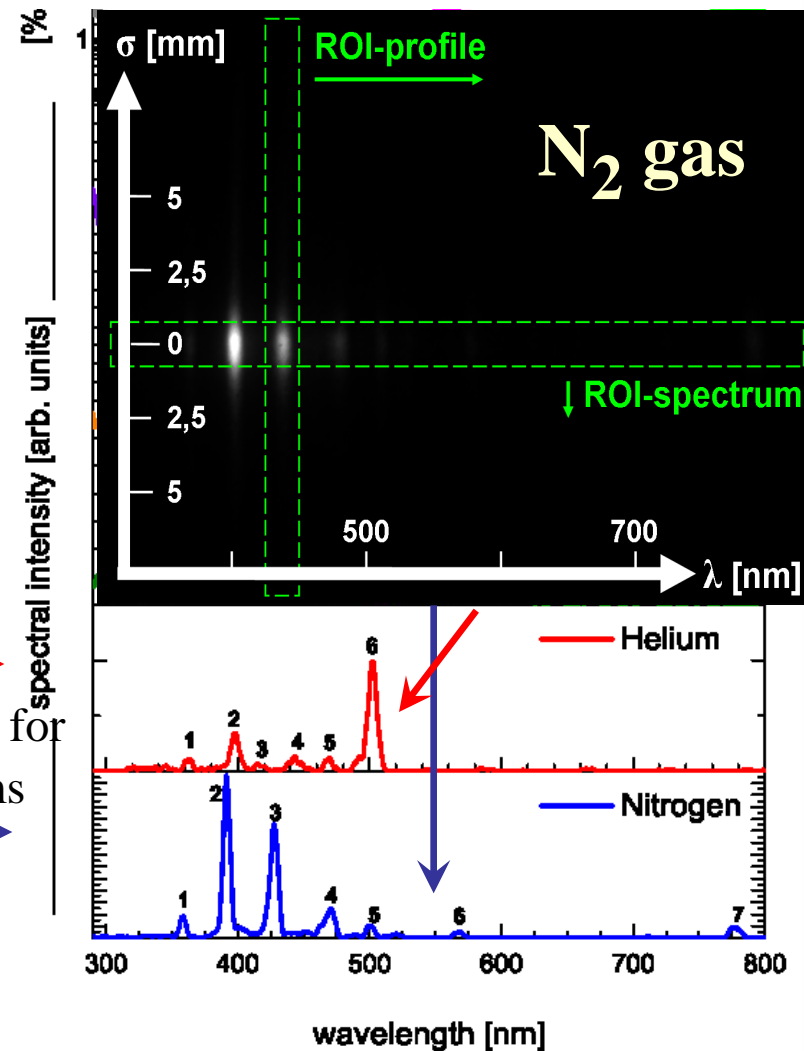


- ⇒ Expected transitions in near-UV to blue
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- ⇒ Same profile reading for all lines
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- ⇒ *N₂ is well suited!*

Normalized profile reading for all λ :



Beam parameter: S⁶⁺ at 5.16 MeV/u with $3 \cdot 10^{11}$ pps,
2000 macro-pulses, $p_{N_2} = 10^{-3}$ mbar



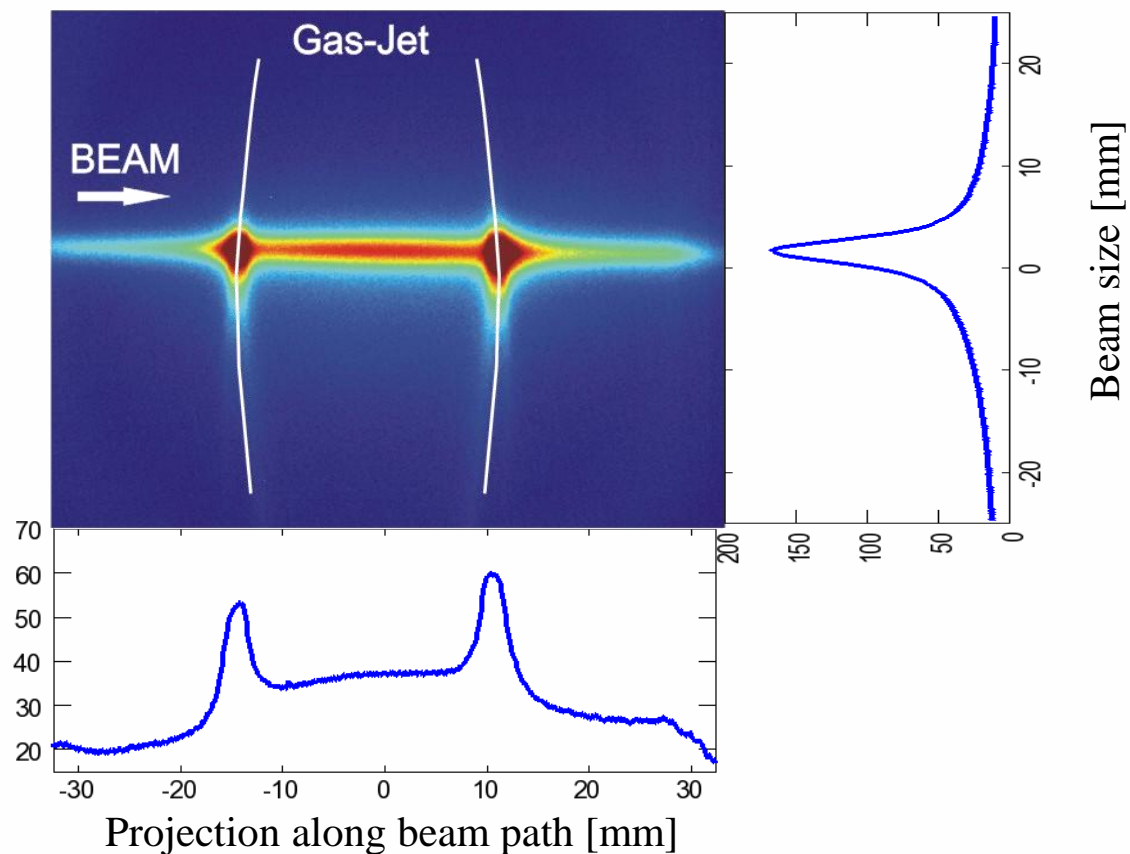
Usage as a Diagnostics of a Gas Target



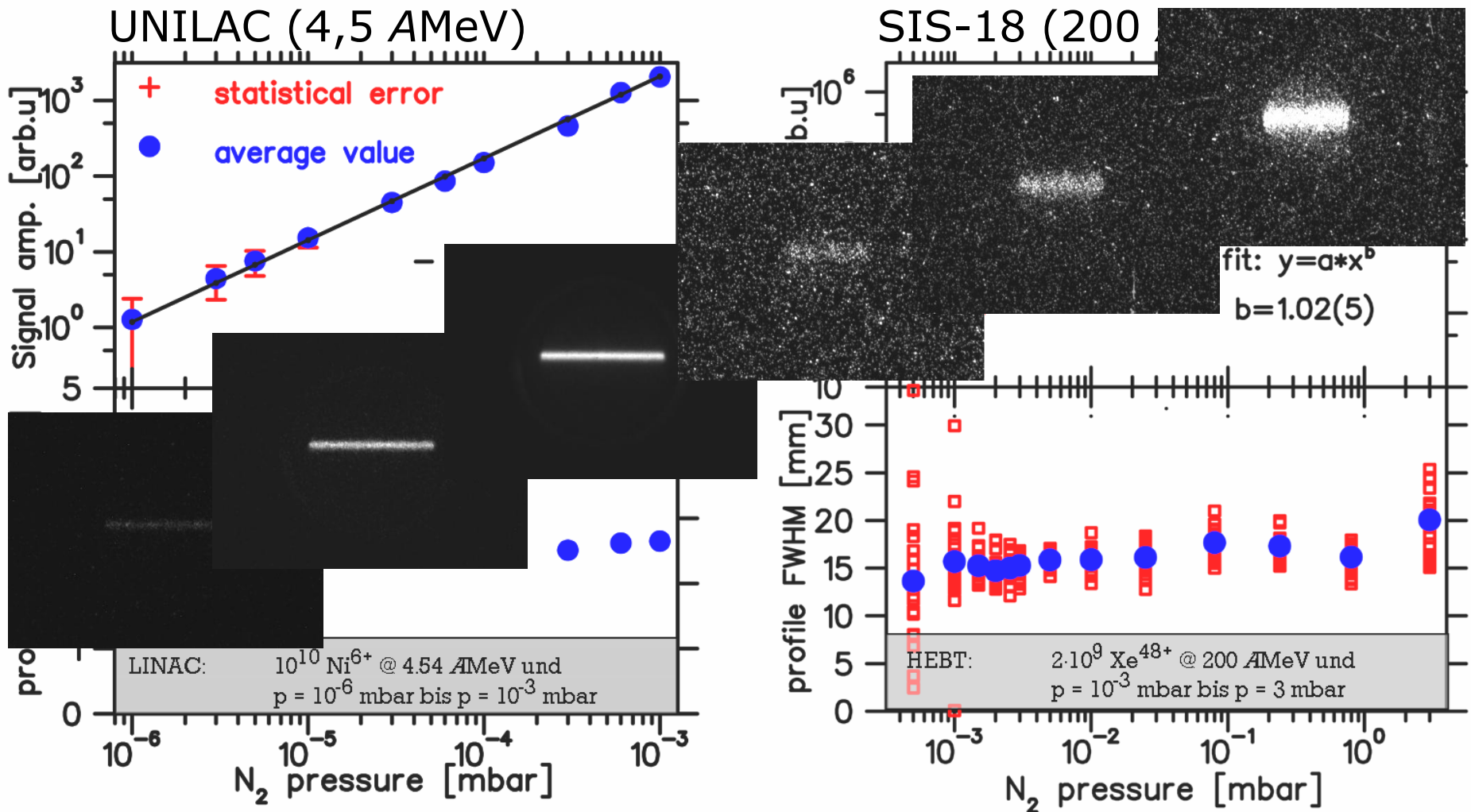
The properties of a gas target including beam overlap can be monitored:

The light yield is proportional to beam current x gas density

Example: UNILAC Gas stripper at 1.4 MeV/u



Pressure-Variation by 6 OM



Amplitude $\sim p$ and $\sigma = \text{constant} \rightarrow p$ is a free parameter